

# Ferromagnetic 0– $\pi$ Josephson junctions

M. Weides<sup>1</sup>, H. Kohlstedt<sup>1</sup>, R. Waser<sup>1</sup>, M. Kemmler<sup>2</sup>, J. Pfeiffer<sup>2</sup>, D. Koelle<sup>2</sup>, R. Kleiner<sup>2</sup>, E. Goldobin<sup>2</sup>

<sup>1</sup> Center of Nanoelectronic Systems for Information Technology (CNI), Research Centre Jülich, D-52425 Jülich, Germany

<sup>2</sup> Physikalisches Institut-Experimentalphysik II, Universität Tübingen, Auf der Morgenstelle 14, D-72076 Tübingen, Germany

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**Abstract** We present a study on low- $T_c$  superconductor-insulator-ferromagnet-superconductor (SIFS) Josephson junctions. SIFS junctions have gained considerable interest in recent years because they show a number of interesting properties for future classical and quantum computing devices. We optimized the fabrication process of these junctions to achieve a homogeneous current transport, ending up with high-quality samples. Depending on the thickness of the ferromagnetic layer and on temperature, the SIFS junctions are in the ground state with a phase drop either 0 or  $\pi$ . By using a ferromagnetic layer with variable step-like thickness along the junction, we obtained a so-called 0- $\pi$  Josephson junction, in which 0 and  $\pi$  ground states compete with each other. At a certain temperature the 0 and  $\pi$  parts of the junction are perfectly symmetric, i.e. the absolute critical current densities are equal. In this case the degenerate ground state corresponds to a vortex of supercurrent circulating clock- or counterclockwise and creating a magnetic flux which carries a fraction of the magnetic flux quantum  $\Phi_0$ .

## 1 Introduction

Superconductivity (S) and ferromagnetism (F) are two competing phenomena. On one hand a bulk superconductor expels the magnetic field (Meissner effect). On the other hand the magnetic field for  $H > H_{c2}$  destroys the superconductivity. This fact is due to the unequal symmetry in time: ferromagnetic order breaks the time-reversal symmetry, whereas conventional superconductivity relies on the pairing of time-reversed states. It turns out that the combination of both, superconductor and ferromagnet, leads to rich and interesting physics. One particular example – the phase oscillations of the superconducting Ginzburg-Landau order parameter inside the ferromagnet – will play a major role for the devices discussed in this work.

The current-phase relation  $I_s(\phi)$  of a conventional SIS Josephson junction (JJ) is given by  $I_s(\phi) = I_c \sin(\phi)$ .  $\phi = \theta_1 - \theta_2$  is the phase difference of the macroscopic superconducting wave functions  $\Psi_{1,2} = \sqrt{n_s} e^{i\theta_{1,2}}$  (order-parameters of each electrode) across the junction,  $I_c$  is the critical current. Usually  $I_c$  is positive and the minimum of the Josephson energy  $U = E_J(1 - \cos \phi)$ ,  $E_J = \frac{I_c \Phi_0}{2\pi}$  is at  $\phi = 0$ . However, Bulaevskii *et al.* [1] calculated the supercurrent through a JJ with ferromagnetic impurities in the tunnel barrier and predicted a negative supercurrent,  $I_c < 0$ . For  $-I_c \sin(\phi) = 0$  the solution  $\phi = 0$  is unstable and corresponds to the maximum energy  $U = E_J(1 + \cos \phi)$ , while  $\phi = \pi$  is stable and corresponds to the ground state. Such JJs with  $\phi = \pi$  in ground state are called  $\pi$  junctions, in contrast to conventional 0 junctions with  $\phi = 0$ . In case of a  $\pi$  Josephson junction the first Josephson relation is modified to  $I_s(\phi) = -I_c \sin(\phi) = I_c \sin(\phi + \pi)$ . In experiment the measured critical current in a single junction is always positive and is equal to  $|I_c|$ . It is not possible to distinguish 0 JJs from  $\pi$  JJs from the current-voltage characteristic (IVC) of a single junction. The particular  $I_c(T)$  [2] and  $I_c(d_F)$  [3] dependencies for SFS/SIFS type junction are used to determine the  $\pi$  coupled state. For low-transparency SIFS junctions the  $I_c(d_F)$  dependence is given by

$$I_c(d_F) \propto \exp\left(\frac{-d_F}{\xi_{F1}}\right) \cos\left(\frac{d_F - d_F^{\text{dead}}}{\xi_{F2}}\right), \quad (1)$$

where  $\xi_{F1}, \xi_{F2}$  are the decay and oscillation lengths of critical current and  $d_F^{\text{dead}}$  is the dead magnetic layer thickness [4]. For  $\frac{1}{2}\xi_{F2}\pi < d_F - d_F^{\text{dead}} < \frac{3}{2}\xi_{F2}\pi$  the coupling in ground state of JJs is shifted by  $\pi$ .

In a second work Bulaevskii *et al.* [5] predicted the appearance of a *spontaneous* supercurrent at the boundary between a 0 and a  $\pi$  coupled long JJ (LJJ). This supercurrent emerges in the absence of a driving bias current or an external field  $H$ , i.e. in the ground state. Depending on the length of the junction  $L$  the supercurrent carries one half of the flux quantum, i.e.  $\Phi_0/2$  (called

*semifluxon*), or less. Fig. 1(a) depicts the cross section of a symmetric  $0-\pi$  long JJ. The spontaneous supercurrent  $j_s$  flows either clockwise or counterclockwise, creating the magnetic field of  $\pm\Phi_0/2$ . The current density jumps from maximum positive to maximum negative value at the  $0-\pi$  phase boundary. A theoretical analysis based on the perturbed sine-Gordon equation is given in Ref. [6]. Below we will first discuss the properties of the spontaneous supercurrent and, second, various systems having  $0-\pi$  phase boundaries.

*Spontaneous supercurrent* Kirtley *et al.* [7] calculated the free energy of  $0-\pi$  JJs for various lengths of the 0 and  $\pi$  parts as a function of the normalized length  $\ell = L/\lambda_J$  and the degree of asymmetry  $\Delta = |j_c^\pi|L_\pi/|j_c^0|L_0$ , where  $j_c^0, j_c^\pi$  are the critical current densities and  $L_0, L_\pi$  are the lengths of 0 and  $\pi$  parts respectively, so that  $L = L_0 + L_\pi$ . The state of a *symmetric*  $0-\pi$  junction ( $\Delta = 1$ ) with spontaneous flux has lower energy than the states  $\phi = 0$  or  $\phi = \pi$  without flux. Symmetric  $0-\pi$  junctions have

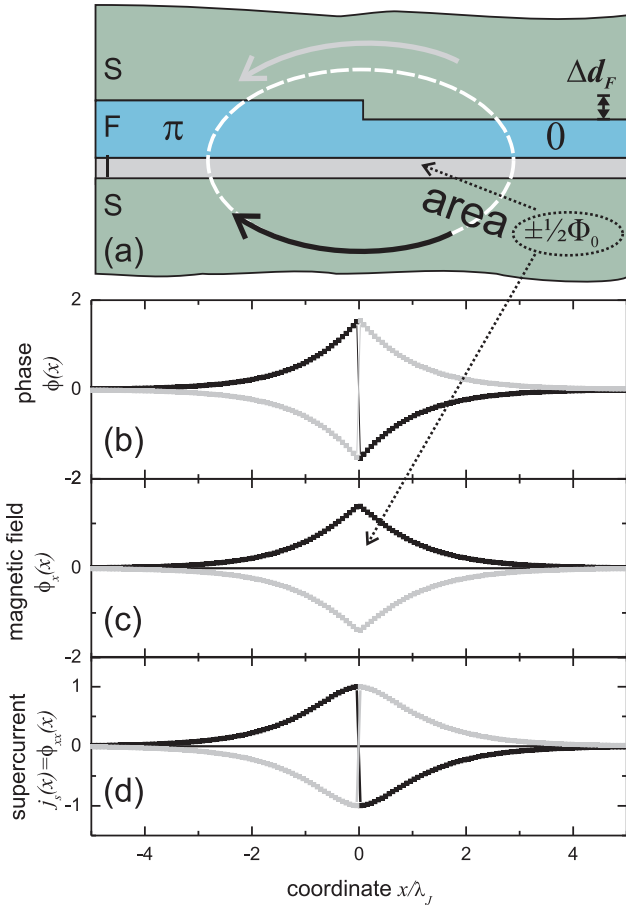
*always* some self-generated spontaneous flux, although its amplitude vanishes for  $L \rightarrow 0$  as  $\Phi \approx \Phi_0 \ell^2/8\pi$ . For example, a symmetric  $0-\pi$  JJ of the total length  $L = \lambda_J$  has a spontaneous magnetic flux  $\Phi \approx 0.04\Phi_0$  and a symmetric  $0-\pi$  JJ with  $L = 8\lambda_J$  has a spontaneous flux of some 2–3% below  $\Phi_0/2$ . Only in case of a infinitely long JJ we refer to the spontaneous flux as *semifluxons*, for shorter JJs it is named *fractional vortex*.

The supercurrent or magnetic flux can be directly detected by measuring  $I_c(H)$  [7], by scanning SQUID (superconducting quantum interference device) microscopy (in the LJJ limit, see [8, 9]) or by LTSEM (low temperature scanning electron microscopy) [10].

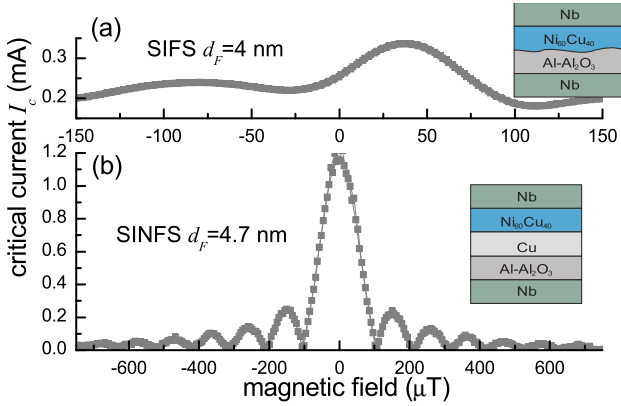
*$0-\pi$  junctions technology*  $0-\pi$  Josephson junctions with a spontaneous flux in the ground state are realized with various technologies. The presence of fractional vortex has been demonstrated experimentally in *d*-wave superconductor based ramp zigzag junctions [9], in long Josephson  $0-\pi$  junctions fabricated using the conventional Nb/-Al-Al<sub>2</sub>O<sub>3</sub>/Nb technology with a pair of current injectors [11], in the so-called tricrystal grain-boundary LJJs [8, 12, 13] or in SFS/SIFS JJs [14, 15, 16] with *stepped* ferromagnetic barrier as in Fig. 1. In the latter systems the Josephson phase in the ground state is set to 0 or  $\pi$  by choosing proper F-layer thicknesses  $d_1, d_2$  for 0 and  $\pi$  parts, i.e. the amplitude of the critical current densities  $j_c^0$  and  $j_c^\pi$  can be controlled to some degree. The advantages of this system are that it can be prepared in a multilayer geometry (allowing topological flexibility) and it can be easily combined with the well-developed Nb/Al-Al<sub>2</sub>O<sub>3</sub>/Nb technology.

The starting point for estimation of the ground state of a *stepped* JJ is studying the IVCs and  $I_c(H)$  for the *planar* reference 0 and  $\pi$  JJs. From this one can calculate important parameters such as the critical current densities  $j_c^0, j_c^\pi$ , the Josephson penetration depths  $\lambda_J^0, \lambda_J^\pi$  and the ratio of asymmetry  $\Delta$ . For  $0-\pi$  junctions one needs 0 and  $\pi$  coupling in *one* junction, setting high demands on the fabrication process. The ideal  $0-\pi$  JJ would have equal  $|j_c^0| = |j_c^\pi|$  and a  $0-\pi$  phase boundary in its center to have a symmetric situation. Furthermore the junctions should be underdamped (SIFS structure) since low dissipation is necessary to study dynamics and eventually macroscopic quantum effects. The junctions should have a high  $j_c$  (and hence small  $\lambda_J \propto \sqrt{j_c}$ ) to reach the LJJ limit and to keep high  $V_c = I_c R$  products, where  $V_c$  is the characteristic voltage and  $R$  the normal state resistance.

Previous experimental works on  $0-\pi$  JJs based on SFS technology [14, 15] gave no information about  $j_c^0$  and  $j_c^\pi$ . Hence, the Josephson penetration depth  $\lambda_J$  could not be calculated for these samples and the ratio of asymmetry  $\Delta$  was unknown. The first intentionally made symmetric  $0-\pi$  tunnel JJ of SIFS type with a large  $V_c$  was realized by the authors [16], making direct transport measure-



**Fig. 1** (a) Sketch of a  $0-\pi$  SIFS JJ with step-like thickness of F-layer and circulating supercurrent  $j_s$  around  $0-\pi$  phase boundary. The junction length  $L \gg \lambda_J$ , therefore the spontaneous flux (area below magnetic field) is equal to half of a flux quantum  $\Phi_0$  (semifluxon). (b)-(d) depicts the phase  $\phi(x)$ , magnetic field  $\phi_x(x)$  and supercurrent  $j_s(x) = \frac{I_c}{|I_c|} \sin \phi$  of the  $0-\pi$  junction.



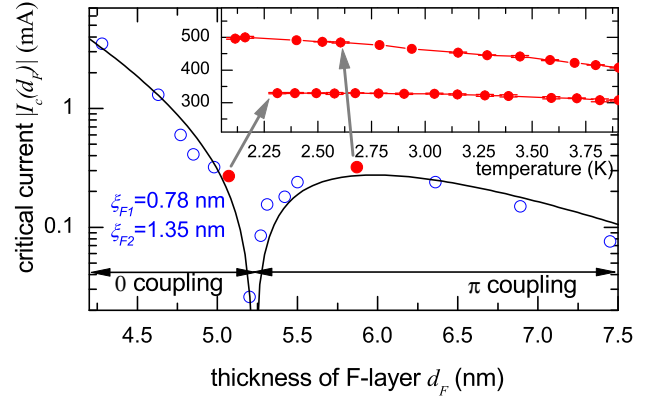
**Fig. 2** (Color online)  $I_c(H)$  of (a) SIFS (4 nm NiCu) and (b) SINFS (Cu 2 nm, NiCu 4.7 nm) stacks. Oxygen pressure is 0.45 mbar for SIFS and 0.015 mbar for SINFS type.

ments of  $I_c(H)$  and calculation of the ground state with spontaneous flux feasible.

Within this paper we *review* the physics of  $0-\pi$  coupled SIFS-type Josephson junctions and give an overview on our experimental results. Special focus is put on the fabrication of SIFS junctions having a planar or stepped-typed ferromagnetic layer (NiCu), the determination of ground state (0 or  $\pi$  for planar JJs) and asymmetry of critical currents (stepped JJs). Finally we give an estimation of the spontaneous magnetic flux in the ferromagnetic  $0-\pi$  JJs.

## 2 Fabrication

The fabrication process for *planar* junctions is based on Nb/ $\text{Al}-\text{Al}_2\text{O}_3$ /NiCu/Nb stacks, deposited by dc magnetron sputtering [17]. Thermally oxidized 4-inch Si wafer served as substrate. First of all, a 120 nm thick Nb bottom electrode and a 5 nm thick Al layer were deposited. Second, the aluminium was oxidized for 30 min at room temperature in a separate chamber. Third, the ferromagnet (i.e.  $\text{Ni}_{60}\text{Cu}_{40}$  alloy,  $T_C = 225$  K) was deposited. To have many structures with different thicknesses in one fabrication run, we decided to deposit a *wedge-shaped* F-layer. For this the substrate and sputter target were shifted about half of the substrate diameter. This allowed the preparation of SIFS junctions with a gradient in F-layer thickness in order to minimize inevitable run-to-run variations. The sputtering rates for NiCu along the gradient were determined by thickness measurements on reference samples using a Dektak profiler. At the end a 40 nm Nb cap layer was deposited. The tunnel junctions were patterned using a three level optical photolithographic mask procedure and Ar ion-beam milling [18]. The insulation between top and bottom electrode is done by a self-aligned growth of  $\text{Nb}_2\text{O}_5$  insulator by anodic oxidation of Nb after the ion-beam etching. The  $\text{Nb}_2\text{O}_5$  exhibited a defect free insulation between the superconducting electrodes.



**Fig. 3** (Color online)  $I_c(d_F)$  and  $I_c(T)$  (inset) dependences of SIFS junctions at 4.2 K. Note the difference of the slope of  $I_c(T)$  for 0 and  $\pi$  coupled junction (inset).

Topological and electrical measurements, see Ref. [17], indicated that the direct deposition of NiCu on the tunnel barrier (SIFS-stacks) led to an anomalous  $I_c(H)$  dependence such as shown in Fig. 2(a), which is an indication for an inhomogeneous current transport. An additional 2 nm thin Cu layer between the  $\text{Al}_2\text{O}_3$  tunnel barrier and the ferromagnetic NiCu (SINFS-stacks) brought considerable benefits, as it ensured a homogeneous current transport, see Fig. 2(b). In this way a high number of functioning devices with  $j_c$  spreads less than 2% was obtained. The variation of the F-layer thickness over a length of one junction diameter is less than 0.02 nm. For simplification we refer in the following to SIFS stacks, although the actual multilayer is SINFS-type.

The patterning of *stepped* junctions was done after the complete deposition of the planar SIFS stack and before the definition of the junction mesa by argon-etching and  $\text{Nb}_2\text{O}_5$  insulation. The detailed process is published in Ref. [19]. The junction was partly protected with photoresist to define the step location in the F-layer, followed by i) *selective reactive etching* of the Nb, ii) *ion-etching* of the NiCu by  $\Delta d_F$  and iii) subsequent *in situ* deposition of Nb. To our knowledge, this was the first controlled patterning of  $0-\pi$  JJs based on a ferromagnetic interlayer.

The planar 0,  $\pi$  reference junctions and the stepped  $0-\pi$  junctions were fabricated from a single trilayer.

## 3 SIFS junctions without step-like F-layer

All investigated junctions had an area of  $10\,000\,\mu\text{m}^2$ , but the length and width were different for different junctions. The length was comparable or shorter than the Josephson penetration depth  $\lambda_J$ . We investigated the thickness dependence of the critical current  $I_c(d_F)$ . To produce the  $\text{Al}_2\text{O}_3$  barrier the Al layer was oxidized at 0.015 mbar yielding  $j_c \approx 4.0\,\text{kA}/\text{cm}^2$  for the reference superconductor-insulator-superconductor (SIS) JJs. Then SIFS stacks with wedge-like F-layer were fabricated in

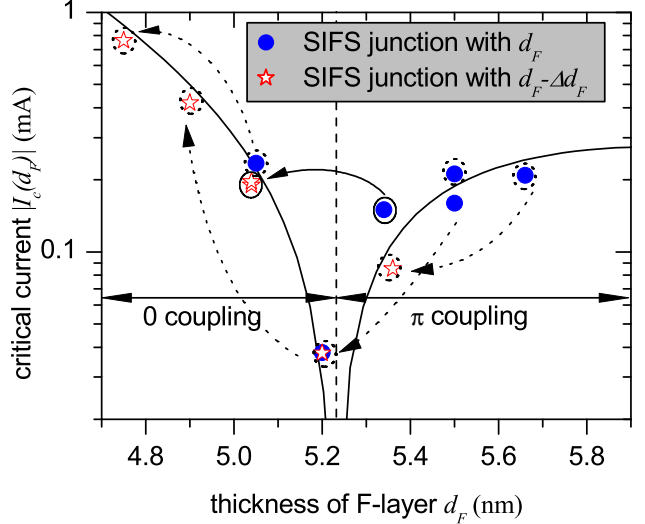
another run. Taking the JJs of the same geometry ( $100 \times 100 \mu\text{m}^2$ ), but situated at different places on the wafer (i.e. different  $d_F$ ) we have measured the nonmonotonic  $I_c(d_F)$  dependence shown in Fig. 3. As a result the fitted parameters are  $\xi_{F1} = 0.78 \text{ nm}$ ,  $\xi_{F2} = 1.35 \text{ nm}$  and  $d_F^{\text{dead}} \approx 3.09 \text{ nm}$ . The coupling changed from 0 to  $\pi$  at the crossover thickness  $d_F^{0-\pi} = \frac{\pi}{2}\xi_{F2} + d_F^{\text{dead}} = 5.21 \text{ nm}$  [4].

The magnetic and spin-orbit scattering in the F-layer mixes the up and down spin states of electrons in the conduction bands. If the spin-flip scattering time  $\tau_s$  is short  $\hbar\tau_s^{-1} \gg k_B T_c$ , like in NiCu alloys, the temperature dependence of scattering provides the dominant mechanism for the  $I_c(T)$  dependence [20]. The oscillation period  $\xi_{F2}$  becomes shorter for decreasing temperature, thus the whole  $I_c(d_F)$  dependence is squeezed to thinner F-layer thicknesses. Hence, the temperature dependence of the critical current  $I_c(T)$  is an interplay between an increasing component due to an increasing gap and a magnetic coupling dependent contribution which may decrease or increase  $I_c$ . The  $I_c(T)$  relations for two JJs (one 0, one  $\pi$ ) are shown in the inset of Fig. 3. At  $d_F = 5.11 \text{ nm}$  the JJ is 0 coupled, but one can relate the nearly constant  $I_c$  below 3.5 K to the interplay between an increasing gap and a decreasing oscillation length  $\xi_{F2}(T)$ . The  $d_F = 5.87 \text{ nm}$  JJ is  $\pi$  coupled and showed a linearly increasing  $I_c$  with decreasing temperature.

#### 4 SIFS junctions with step-like F-layer

Various structures on the wafer were placed within a narrow ribbon perpendicular to the gradient in the F-layer thickness and were replicated along this gradient. One ribbon contained reference JJs with the uniform F-layer thickness  $d_1$  (uniformly etched) and  $d_2$  (non-etched) and a JJ with a step  $\Delta d_F$  in the F-layer thickness from  $d_1$  to  $d_2$ . The lengths  $L_{d_1}$  and  $L_{d_2}$  are both equal to  $167 \mu\text{m}$ . The lithographic accuracy is of the order of  $1 \mu\text{m}$ . A set of structures with difference in  $d_F$  between neighboring ribbons of  $0.05 \text{ nm}$  was obtained. Comparing the critical currents  $I_c$  of non-etched JJs (dots), see Fig. 4 with the experimental  $I_c(d_F)$  data for the etched samples (stars) we estimate the etched-away F-layer thickness as  $\Delta d_F \approx 0.3 \text{ nm}$ . The stars in Fig. 4 are shown already shifted by this amount. Now we choose the set of junctions which have the thickness  $d_2$  and critical current  $I_c(d_2) < 0$  ( $\pi$  junction) before etching and have the thickness  $d_1 = d_2 - \Delta d_F$  and critical current  $I_c(d_1) \approx -I_c(d_2)$  (0 junction) after etching. One option is to choose the junction set denoted by closed circles around the data points in Fig. 4, i.e.  $d_1 = 5.05 \text{ nm}$  and  $d_2 = 5.33 \text{ nm}$ .

The  $I$ - $V$  characteristics and the magnetic field dependence of the critical current  $I_c(H)$  was measured for all three junctions: 0 JJ with  $d_F = d_1$ ,  $\pi$  JJ with  $d_F = d_2$  and  $0-\pi$  JJs with stepped F-layer ( $d_1$  and  $d_2$

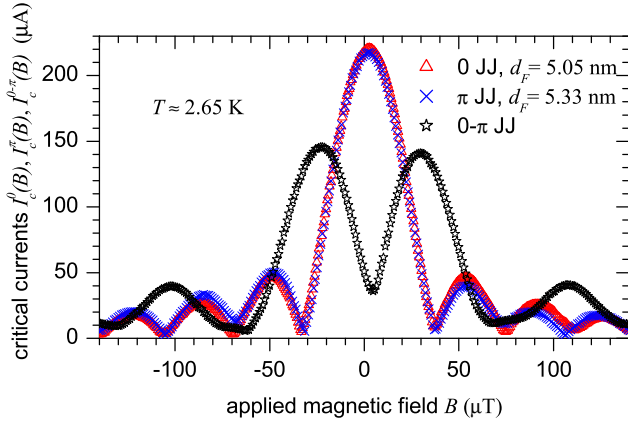


**Fig. 4** (Color online) Critical current  $I_c$  of the uniformly etched (star) and non-etched (dot) SIFS junctions versus the F-layer thickness before etching  $d_F$ . The fit of the experimental data for non-etched samples using Eq.(1) is shown by the continuous line. The JJs were oxidized at 0.015 mbar.

in each half). The magnetic diffraction pattern  $I_c(H)$  of the  $0-\pi$  JJ and the 0 and  $\pi$  reference JJs are plotted in Fig. 5. The magnetic field  $H$  was applied in-plane of the sample and parallel to the step in the F-layer. Due to a small net magnetization of the F-layers the  $I_c(H)$  of reference junctions were slightly shifted along the  $H$  axis. Nevertheless, both had the same oscillation period  $\mu_0 H_{c1} \approx 36 \mu\text{T}$ . At  $T \approx 4.0 \text{ K}$  the  $0-\pi$  JJs was slightly asymmetric with  $I_c^0 \approx 208 \mu\text{A}$  and  $I_c^\pi \approx 171 \mu\text{A}$  (data of reference JJs). To achieve a more symmetric configuration, the bath temperature was reduced, because a decrease in temperature should increase  $I_c^\pi = I_c(d_2)$  more than  $I_c^0 = I_c(d_1)$ , like for the 0 and  $\pi$  samples in the inset of Fig. 3. As a result, both  $I_c^0(T)$  and  $I_c^\pi(T)$  were increasing when decreasing the temperature, but with different rates. At  $T \approx 2.65 \text{ K}$  the critical currents  $I_c^0$  and  $I_c^\pi$  became approximately equal, see Fig. 5. The magnetic field dependence of the planar reference junctions  $I_c^0(H)$  and  $I_c^\pi(H)$  look like perfect Fraunhofer patterns. One can see that the  $I_c^0(H)$  and  $I_c^\pi(H)$  measurements almost coincide, having the form of a symmetric Fraunhofer pattern with the critical currents  $I_c^0 \approx 220 \mu\text{A}$ ,  $I_c^\pi \approx 217 \mu\text{A}$  and the same oscillation period. The stepped  $0-\pi$  junction had a magnetic field dependence  $I_c^{0-\pi}(H)$  with a clear minimum near zero field and almost no asymmetry. The critical currents at the left and right maxima ( $146 \mu\text{A}$  and  $141 \mu\text{A}$ ) differ by less than 4 %, i.e. the  $0-\pi$  junction is symmetric, and its ground state in absence of a driving bias or magnetic field ( $I = H = 0$ ) can be calculated [16]. Our symmetric  $0-\pi$  LJJ had an normalized length of  $\ell = 1.3$ , with a spontaneous flux in the ground state of

$$\pm\Phi \approx \Phi_0 \ell^2 / 8\pi \approx 0.067 \cdot \Phi_0,$$





**Fig. 5** (Color online)  $I_c(H)$  of  $0-\pi$  JJ (open triangles) with  $H$  applied parallel to short axis, overlayed with the non-etched (dot) and etched (stars) reference SIFS junction measurements. At  $T \approx 2.65$  K the  $0-\pi$  JJ becomes symmetric. The junction dimensions are  $330 \times 30 \mu\text{m}^2$ .

being equal to 13% of  $\Phi_0/2$ . A detailed calculation taking several deviations from the ideal short JJ model into account can be found elsewhere [21].

## 5 Summary

The concept and realization of  $0-\pi$  junction based on SIFS stacks has been presented. The realization of  $\pi$  coupling in SIFS junctions and the precise combination of 0 and  $\pi$  coupled parts in a single junction has been shown. The coupling of the ferromagnetic Josephson tunnel junctions was investigated by means of transport measurements. The emergence of a spontaneous flux, which was calculated as 13% of half a flux quantum  $\Phi_0/2$ , was observed in the magnetic field dependence of the current-voltage characteristics of the  $0-\pi$  JJ.

As an outlook, the ferromagnetic  $0-\pi$  Josephson junctions allow to study the physics of fractional vortices with a good temperature control of the symmetry between 0 and  $\pi$  parts. We note that symmetry is only needed for JJ lengths  $L \lesssim \lambda_J$ . For longer JJs the semifluxon appears even in rather asymmetric JJs, and  $T$  can be varied in a wide range affecting the semifluxon properties only weakly. The presented SIFS technology allows us to construct 0,  $\pi$  and  $0-\pi$  JJs with comparable  $j_c^0$  and  $j_c^\pi$  in a single fabrication run. Such JJs may be used to construct classical and quantum devices such as oscillators, memory cells,  $\pi$  flux qubits [22, 23] or semifluxon based qubits [24].

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